


<b>Search Notes</b>  	<b>Application/Control No.</b>  10524227	<b>Applicant(s)/Patent Under Reexamination</b>  TANAKA ET AL.
	<b>Examiner</b>  LINH T NGUYEN	<b>Art Unit</b>  2627

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Update searched on East.	4/23/2009	LN

INTERFERENCE SEARCH			
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